MSKSEMI 美森科













ESD

TV

TSS

MOV

GDT

PIFD

MS30N06NF

Product specification





Features

- 60V,30A, RDS(ON)=24mΩ@VGS=10V
- Improved dv/dt capability
- Fast switching
- Green Device Available

Application

- Motor Drive
- Power Tools
- LED Lighting

BVDSS	RDSON	ID
60V	24mΩ	30A

Reference News

PACKAGE OUTLINE	Pin Configuration	Marking
D D D D D D D D D D D D D D D D D D D	G	MSKSEMI 30N06DF MS *** Note:***Representative
DFN5X6-8L		productioncycle

Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V _D S	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
	Drain Current - Continuous (Tc=25°C)	30	А
ID	Drain Current - Continuous (Tc=100°C)	15	А
Ірм	Drain Current - Pulsed ¹	75	А
Po	Power Dissipation (Tc=25°C)	35	W
PD	Power Dissipation - Derate above 25°C	0.32	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Rеja	Thermal Resistance Junction to ambient		62	°C/W
Reuc	Thermal Resistance Junction to Case		3.1	°C/W



Electrical Characteristics (T,=25 °C, unless otherwise noted) Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , ID=250uA	60			V
△BV _{DSS} /△T _J	BVDSS Temperature Coefficient	Reference to 25°C , Io=1mA		0.06		V/°C
Ipss	Drain-Source Leakage Current	V _{DS} =60V , V _{GS} =0V , T _J =25°C			1	uA
IDSS	Brain Godioc Leakage Garrent	V _{DS} =48V , V _{GS} =0V , T _J =125°C			10	uA
Igss	Gate-Source Leakage Current	Vgs= ±20V , Vps=0V			±100	nA

On Characteristics

Rds(on)	Static Drain-Source On-Resistance	Vgs=10V , Ip=10A		24	30	mΩ
1 25(611)		Vgs=4.5V , Ip=5A		25	40	mΩ
V _G S(th)	Gate Threshold Voltage	Vgs=Vps . lp =250uA	1.0	1.6	2.5	V
△VGS(th)	V _{GS(th)} Temperature Coefficient	2004/		-4.6		mV/°C
gfs	Forward Transconductance	V _{DS} =10V , I _D =8A		11		S

Dynamic and switching Characteristics

Qg	Total Gate Charge ^{3,4}		 16.4	
Qgs	Gate-Source Charge ^{3, 4}	Vps=30V , Vgs=10V , Ip=10A	 3.1	 nC
Qgd	Gate-Drain Charge ^{3 , 4}		 3.7	
T _{d(on)}	Turn-On Delay Time ^{3 , 4}		 4.6	
Tr	Rise Time ^{3 , 4}	V_{DD} =30 V , V_{GS} =10 V , R_{G} =6 Ω	 14.8	 ns
T _{d(off)}	Turn-Off Delay Time ^{3, 4}	lo=1A	 27.2	 115
Tf	Fall Time ^{3 , 4}		 7.8	
Ciss	Input Capacitance		 1180	
Coss	Output Capacitance	V _{DS} =30V , V _{GS} =0V , F=1MHz	 80	 pF
Crss	Reverse Transfer Capacitance		 52	

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V _G =V _D =0V , Force Current			30	Α
Ism	Pulsed Source Current	Vo Vb VV , I oloo odilolik			60	Α
Vsp	Diode Forward Voltage	Vgs=0V , Is=1A , T _J =25°C			1.2	V

Note:

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2. V_{DD} =50V, V_{GS} =10V,L=0.1mH, I_{AS} =23A., R_{G} =25 Ω ,Starting T_{J} =25 $^{\circ}$ C
- 3. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- 4. Essentially independent of operating temperature.

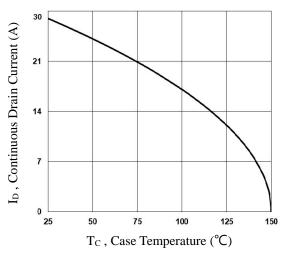


Fig.1 Continuous Drain Current vs. Tc

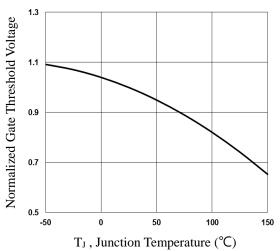


Fig.3 Normalized V_{th} vs. T_J

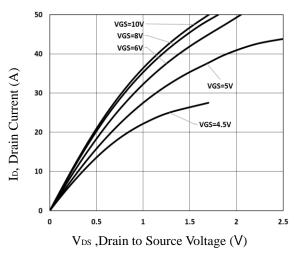


Fig.5 Typical Output Characteristics

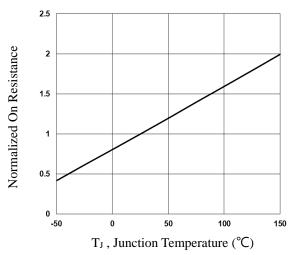


Fig.2 Normalized RDSON vs. TJ

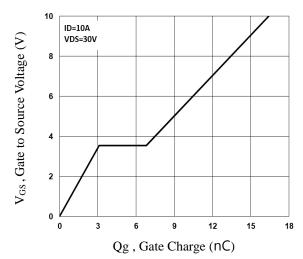


Fig.4 Gate Charge Waveform

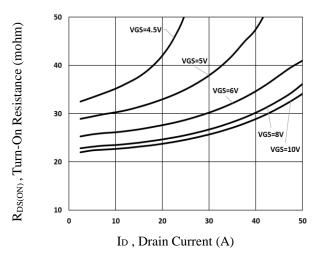


Fig.6 Turn-On Resistance vs. ID

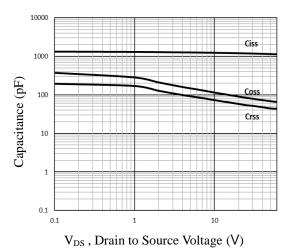


Fig.7 Capacitance Characteristics

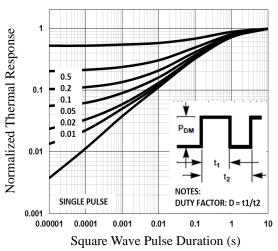


Fig.9 Normalized Transient Impedance

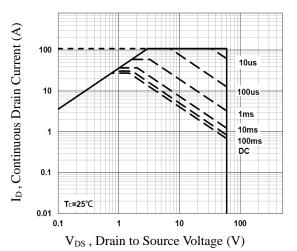
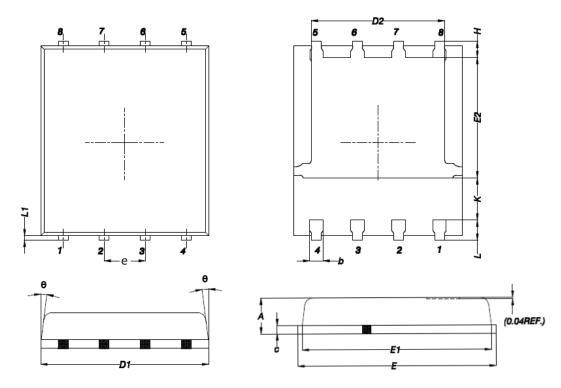


Fig.8 Maximum Safe Operation Area



PDFN5x6-8L PACKAGE INFORMATION



Symbol	Dimensions I	In Millimeters	Dimensions In Inches	
	MAX	MIN	MAX	MIN
Α	1.200	0.850	0.047	0.031
b	0.510	0.330	0.020	0.013
С	0.300	0.200	0.012	0.008
D1	5.400	4.800	0.212	0.189
D2	4.310	3.610	0.170	0.142
E	6.300	5.850	0.248	0.230
E1	5.960	5.450	0.235	0.215
E2	3.920	3.300	0.154	0.130
е	1.27	'BSC	0.05	BSC
Н	0.650	0.380	0.026	0.015
K		1.100		0.043
L	0.710	0.380	0.028	0.015
L1	0.250	0.050	0.009	0.002
θ	12°	0°	12°	0°

REEL SPECIFICATION

P/N	PKG	QTY
MS30N06NF	DFN5X6-8L	5000



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